PCN Number: 2023			3052	22015.1 PCN Date:			May 24, 2023			
Titl	Qualification	of ne	w Fa	v Fab site (FFAB) using qualified Process Technology, Die Revision,						
illi	Datasheet a	nd add	dition	al Assembly BOM op	otions for se	elect	devices	5		
Cus	stomer Contact:	F	PCN M	<u>lanager</u>	Dept:			Quality Services		
Proposed 1 st Ship Date: A			Aug 2	ug 24, 2023 Sample reque accepted unt		-		Jun 24, 2023*		
*Sample requests received after June 24, 2023 will not be supported.										
Change Type:										
Assembly Site As		Assembly Process			Assembly Materials					
\boxtimes	Design			Electrical Specifica	tion		Mechanical Specification			
	Test Site			Packing/Shipping/I	abeling		Test F	Process		
	Wafer Bump Site			Wafer Bump Mater	ial		Wafer Bump Process			
\boxtimes	Wafer Fab Site		\square	Wafer Fab Material	S	\square	Wafer	Fab Process		
				Part number chang	je					

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (FFAB, BICOM3XHV) and assembly BOM options for selected devices as listed below in the product affected section.

Ci	urrent Fab Site	2	Additional Fab Site			
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	
SFAB	JIBB	150 mm	FFAB	BICOM3XHV	200 mm	

The die was also changed as a result of the process change.

Additionally, there will be a BOM/Assembly options introduced for these devices:

	Current	Proposed
Wire type	1.2mil Au	0.8mil Cu
Die Coat	4221706	None
Mount compound	4205846	4147858
Mold compound	4209640	4211880

The datasheets will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The links to the revised datasheets are available in the table below.



INA2128 SBOS035B – DECEMBER 1995 – REVISED MAY 2023

С	hanges from Revision A (April 2007) to Revision B (May 2023) Principal Princ	age
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Added the Package Information table, and the Pin Configuration and Functions, Specifications, Detailed	
	Description, Application and Implementation, Device and Documentation Support, and Mechanical,	
	Packaging, and Orderable Information sections.	
:	Added input voltage noise, high bandwidth, and temperature range bullets to Features Changed Features bullet to show correct package name	
	Changed Applications bullets to show updated links.	
	Changed Package Information table column name from BODY SIZE (NOM) to PACKAGE SIZE and added	
	note regarding the package size	
•	Added single supply specification to Absolute Maximum Ratings	5
•	Added note clarifying output short-circuit to ground in Absolute Maximum Ratings refers to short-circuit to	
	VS / 2	5
•	Added single supply specification to Recommended Operating Conditions	
•	Changed input common-mode voltage range specification from V – 2 to (V–) + 2 in Recommended Operate	
	Conditions	
	Conditions	5
	Added specified temperature range to Recommended Operating Conditions	
	Added test conditions below <i>Electrical Characterstics</i> title	
•	Changed test condition for offset voltage drift specification in Electrical Characteristics from "TA = TMIN to	
	TMAX" to " TA = -40° C to $+85^{\circ}$ C" for clarity	
•	Changed "±0.5±0/G" to "±0.5±20/G" in MAX column of Offset voltage RTI vs temperature row of Electrical Characteristics.	6
	Changed typical long-term stability specification from ±0.1±3/GµV/mo to ±0.2±3/GµV/mo in Electrical	
	Characteristics	
•	Deleted typical specification and changed common-mode voltage specification from (V-) + 2 V minimum a	nd
	(V+) – 2 V maximum across one row in Electrical Characteristics	6
•	Deleted typical VCM specifications in Electrical Characteristics	6
•	Added test condition of "RS = 0 Ω" to safe input voltage specification in Electrical Characteristics for clarity	
•	Changed parameter name to Input bias current and added test condition "TA = -40°C to +85°C" to input bi current drift specification in <i>Electrical Characteristics</i> for clarity	
•	Changed parameter name to Input offset current drift and added test condition "TA = -40°C to +85°C" to in	put
	offset current drift specification in Electrical Characteristics for clarity	6
•	Changed maximum gain error specification for INA128PA/UA and INA129PA/UA with G = 1 from ±0.01% t	0
	±0.1% in Electrical Characteristics	6
•	Changed parameter name to Gain drift and added test condition "TA = -40° C to $+85^{\circ}$ C" for gain drift in	
	Electrical Characteristics for clarity Changed parameter names from "Voltage - Positive" to "Positive output voltage swing" and from "Voltage -	
•	Negative to "Negative output voltage swing" in <i>Electrical Characteristics</i>	6
	Deleted typical positive and negative output voltage swing specifications in <i>Electrical Characteristics</i>	6
	Added test condition "Continuous to VS / 2" short-circuit current specification in <i>Electrical Characteristics</i>	
	for clarity	6
•	Changed typical bandwidth specification for G = 10 from 700 kHz to 600 kHz in Electrical Characteristics	6
•	Changed typical slew rate specification from 4 V/µs to 1.2 V/µs in Electrical Characteristics	6
•	Changed typical settling time specification for G = 1, G = 10, from 7 μ s to 9 μ s in <i>Electrical Characteristics</i>	-
	Deleted parameter "Temperature Range" as made redundant by "Recommended Operating Conditions" an	
•	"Absolute Maximum Ratings"	
-	temperature range, and specification temperature range specifications from <i>Electrical Characteristics</i>	6
•	Added test conditions below the Typical Characteristics title	
•	Changed Figure 6-1, Gain vs Frequency	
•	Changed Figure 6-3, Positive Power Supply Rejection vs Frequency	
•	Changed Figure 6-4, Negative Power Supply Rejection vs Frequency	
•	Changed Figure 6-7, Crosstalk vs Frequency	
•	Changed Figure 6-8, Input-Referred Voltage Noise vs Frequency	
•	Changed Figure 6-9, Settling Time vs Gain	
•	Changed Figure 6-11, Input Overvoltage V/I Characteristics	
•	Changed Figure 6-12, Offset Voltage Warm-Up	
•	Changed Output Voltage Swing vs Output Current, into two separate plots, one for positive (Figure 6-14) a	
	one for negative (Figure 6-15) Changed Figure 6-22 to Figure 6-24, Large-Signal Step Response	
_	enangee righte e zz to righte e zh, zarge eight otep neepenee	

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet	
INA2128	SBOS035A	SBOS035B	http://www.ti.com/product/INA2128	

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings:

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

	RoHS	REACH	Green Status	IEC 62474				
	🛛 No Change	🛛 No Change	🛛 No Change	🛛 No Change				
С	Changes to product identification resulting from this PCN:							

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
FR-BIP-1	TID	DEU	Freising

Die Rev:

Current	New			
Die Rev [2P]	Die Rev [2P]			
Α	Α			

Sample product shipping label (not actual product label)

INSTRUMENTS MADE IN: Malaysia 2DC: 20: MSL '2 /260C/1 YEAR SEAL D MSL 1 /235C/UNLIM 03/29/ 0PT: 39	INSTRUMENTS G4 MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39		SN74LSO7NSR 2000 (D) 0336 (D) 0336 (D) LOT: 3959047MLA (TKY(1T) 7523483S12 REV: (V) 0033317 (CSO: CHE (21L) CCO-USA ASO: MLA (23L) ACO: MYS	
Product Affected:				
INA2128U INA2128U/1K	INA2128UA		INA2128UA/1K	INA2128UG4

For alternate parts with similar or improved performance, please visit the product page on $\underline{\text{TI.com}}$

Qualification Report Approve Date 21-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: INA2128U/1K	QBS Process Reference: <u>OPA202ID</u>	QBS Process Reference: <u>INA828ID</u>	QBS Process Reference: INA821ID	QBS Process Reference: <u>OPA207ID</u>	QBS Package Reference: <u>MUX36S16IDW</u>	QBS Package Reference: <u>MUX506IDW</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	3/231/0	3/231/0	2/153/0	1/77/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	1/77/0	3/231/0	3/231/0	3/231/0	3/231/0	2/154/0	1/77/0
тс	A4	Temperature Cycle	-65/150C	500 Cycles	1/77/0	3/231/0	3/231/0	3/231/0	3/231/0	-	-
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0	3/231/0	3/231/0	3/231/0	2/154/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/231/0	3/231/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	3/231/0	2/154/0	1/77/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	3/231/0	3/231/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/6/0	2/12/0	1/6/0	1/6/0	1/3/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	3/90/0	3/90/0	1/30/0	1/30/0	1/30/0

QBS: Qual By Similarity

Qual Device INA2128U/1K is qualified at MSL1 260C

· Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail				
WW Change Management Team	PCN ww admin team@list.ti.com				

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